Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

# 2SK3398

# Switching Regulator and DC-DC Converter Applications Motor Drive Applications

• Low drain-source ON resistance: RDS (ON) =  $0.4 \text{ m}\Omega$  (typ.)

• High forward transfer admittance:  $|Y_{fs}| = 9.0 \text{ S (typ.)}$ 

• Low leakage current:  $IDSS = 100 \mu A (max) (VDS = 500 V)$ 

• Enhancement-mode:  $V_{th} = 2.0 \text{ to } 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$ 

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	500	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	500	V	
Gate-source voltage		$V_{GSS}$	±30	V	
Drain current	DC (Note 1)	ID	12	Α	
	Pulse (Note 1)	I <sub>DP</sub>	48	A	
Drain power dissipation (Tc = 25°C)		$P_{D}$	100	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	364	mJ	
Avalanche current		I <sub>AR</sub>	12	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	10	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55 to150	°C	

9.2 max
7.0±0.2

1.0±0.2 1.0±0

Weight: 0.74 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### Thermal Characteristics

Characteristics	Symbol	Max	Unit	
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	1.25	°C/W	

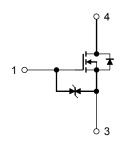
Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = 90~V,~T_{ch} = 25^{\circ}C$  (initial), L = 5.85 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = 12 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

#### **Circuit Configuration**



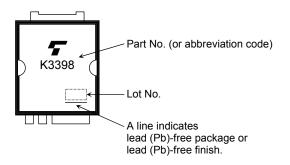
## **Electrical Characteristics (Ta = 25°C)**

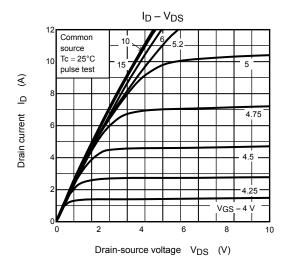
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30	_	_	V
Drain cut-OFF cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V	_	_	100	μА
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 10$ mA, $V_{GS} = 0$ V	500	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6 A	_	0.4	0.52	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 6 A	4.0	9.0	_	S
Input capacitance	)	C <sub>iss</sub>		_	2040	_	pF
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	200	_	
Output capacitance		Coss		_	630	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $0 \text{ V}$ $V_{GS}$ $0 \text{ V}$ $0  V$	_	22	_	- ns
	Turn-ON time	t <sub>on</sub>		_	58	_	
	Fall time	t <sub>f</sub>		_	36	_	
	Turn-OFF time	t <sub>off</sub>		_	180	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	45	_	nC
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		25		
Gate-drain ("miller") charge		Q <sub>gd</sub>			20		

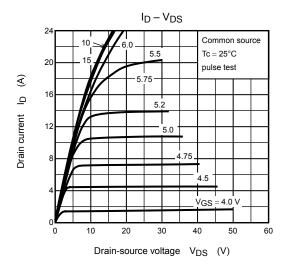
# **Source-Drain Ratings and Characteristics (Ta = 25°C)**

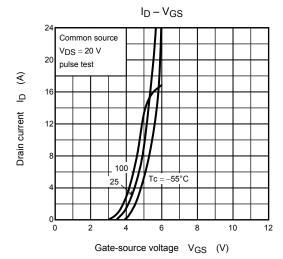
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	$I_{DR}$	_	_	_	12	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	48	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 12 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	$I_{DR} = 12 \text{ A}, V_{GS} = 0 \text{ V},$	_	1200	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/μs	_	16	_	μС

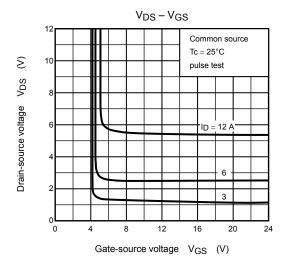
## Marking

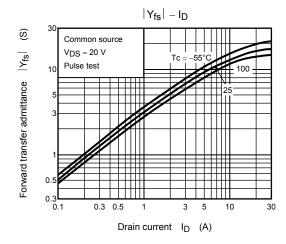


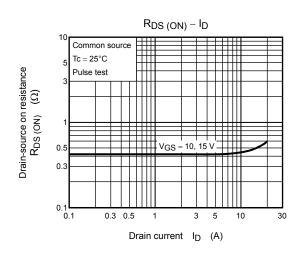


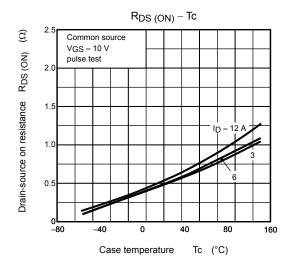


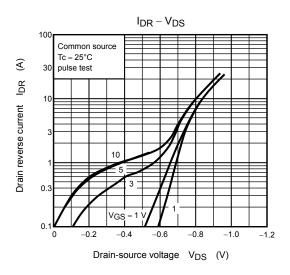


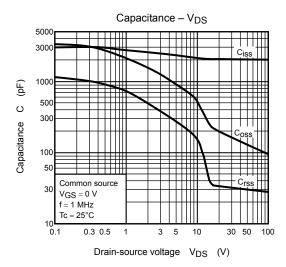


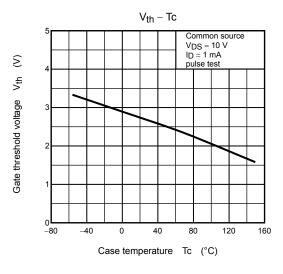


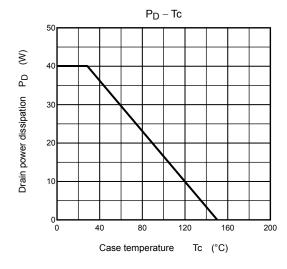


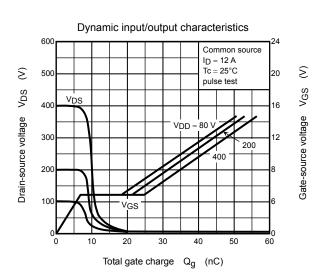


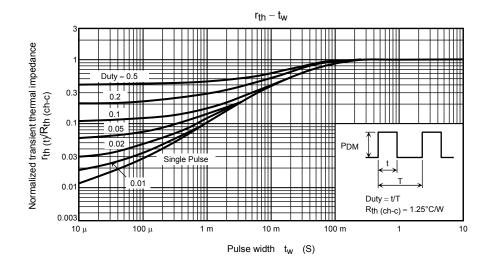


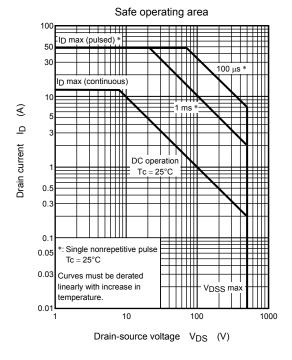


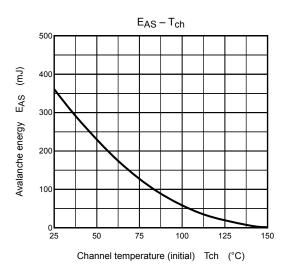


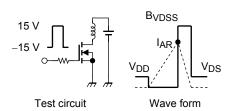












$$R_G = 25~\Omega$$
  
 $V_{DD} = 90~V,~L = 4.3~mH$ 

$$\mathsf{EAS} = \frac{1}{2} \cdot L \cdot l^2 \cdot \left( \frac{\mathsf{BVDSS}}{\mathsf{BVDSS} - \mathsf{VDD}} \right)$$

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